



## Supporting Information

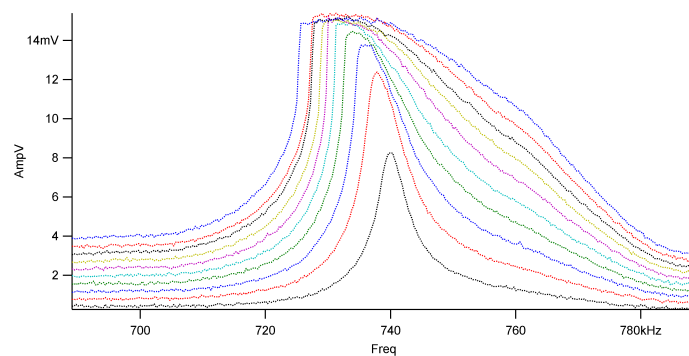
for

### **Cantilever signature of tip detachment during contact resonance AFM**

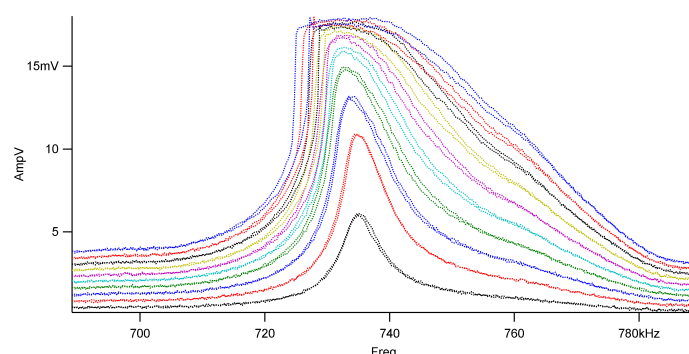
Devin Kalafut, Ryan Wagner, Maria Jose Cadena, Anil Bajaj and Arvind Raman

*Beilstein J. Nanotechnol.* **2021**, *12*, 1286–1296. doi:10.3762/bjnano.12.96

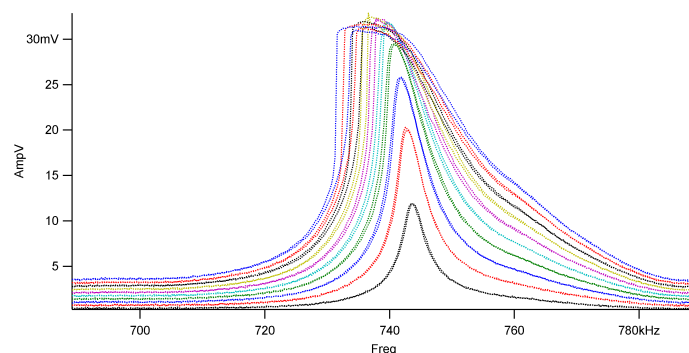
### **Additional AFM measurements**



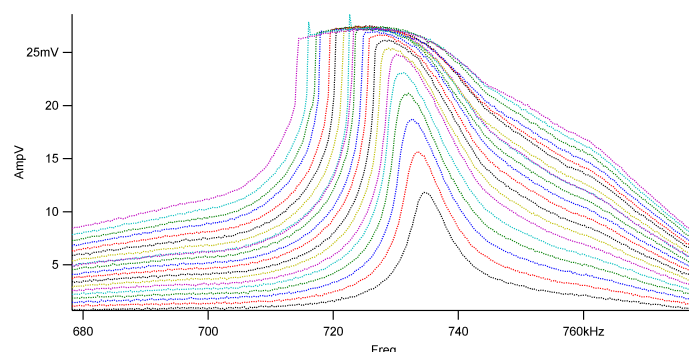
(a)



(b)



(c)



(d)

Figure S1: Additional evidence of tip-sample detachment on silicon samples at various piezoelectric drive amplitudes, shown as photodiode detector amplitude vs drive frequency.